Atty. Dkt.: 1232-5317

IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the

application:

1. (Original) An aberration measuring method in which a light flux converged by a condensing

optical system is made incident on an optical system to be measured, the light flux that has

passed through said optical system to be measured is reflected by a reflecting optical system

having a center of curvature at a light convergence point on a light emergence side of said optical

system to be measured is made incident on said optical system to be measure again, and

wavefront aberration of said optical system to be measured is detected as interference fringes

using the light flux that has passed through said optical system to be measured again,

comprising:

a step of setting a numerical aperture of said optical system to be measured to a numerical

aperture larger than a maximum numerical aperture in a case that said optical system is actually

used; and

a step of measuring wavefront aberration of said optical system at a set numerical

aperture.

2. (Original) An aberration measuring method according to claim 1, wherein letting NA₀ be said

maximum numerical aperture in the case that said optical system to be measured is actually used

and letting NA₁ be said set numerical aperture, the following condition is satisfied:

 $NA_0/NA_1 < 0.995$.

3-5. (Cancelled)

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